



TestForum 2012

Borupgaard, Snekkersten, Denmark
27-28 November, 2012

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Test Forum 2012 Local Organizer

Birger Schneider
Chamaj Consult
Phone: +45 40 55 21 00
E-mail: birger.schneider@chamaj.com

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Nordic Test Forum

Call for Papers / Presentations

The 2-day TestForum 2012, the 12th event in the series, is a major event for Test professionals in the Nordic area and Baltic states. Every year the TestForum is attended by key people from the industry's test community as well as by international vendors of test and measurement equipment and solutions.

The event will take place at Borupgaard, Snekkersten, Denmark, (just south of Helsingør). Nordic Test Forum hereby cordially invites you to participate and submit your contribution to TestForum 2012, which includes (but is not limited to) the following topics:

- *Functional test*
- *RF testing*
- *ICT / Flying Probe*
- *Power testing*
- *Fixturing/interfaces*
- *Boundary-Scan test*
- *Test economics*
- *AOI / AXI*
- *Preventive test / Prognostics*
- *Best practices in manufacturing test*
- *Embedded Test*
- *ASIC: BIST / Mixed-signal / IDDQ / IDDT*
- *Board test SW, BIST, diagnostics*
- *Design to Test transfer / Design for Testing*
- *Quality methods and tools*
- *ESD*
- *Test efficiency and optimization*
- *Future technology trends and test challenges*
- *Data acquisition / collection / analysis*

Submissions

NTF seeks for full papers and/or presentations in the area of test of electronics, including *R&D, Application Contributions, Best Practices, Emerging Ideas*, etc. You are welcome to submit contributions also outside the above topics as long as they stay within the field of electronics test. Focus shall be on new and upcoming challenges, best practices in electronic test engineering, opportunities and techniques rather than on particular products.

Proceedings

At the event, Nordic Test Forum will deliver on electronic format the accepted contributions of authors that wish to provide the corresponding materials.

The Format of the Event

- The event duration will be a two-day workshop and a small exhibition attached to it.
- November 26th on the evening there is the AGM of the NTF.
- The mix of presentations will decide the number of sessions.
- The presentations will be 30 minutes each: 25 minutes of actual presentation and 5 minutes for questions and comments.
- During the exhibition, attendees will have a chance to see the latest equipment and talk to exhibitors.

Key Dates

- Abstract submission:
- Notification of acceptance:
- Presentation slides:

August 19th, 2012
September 30th, 2012
November 4th, 2012

Further Information and Submissions

Suzanne Holte
Phone: +45 2088 5972
Email: suzanne@nordicestforum.org

Visit the NTF web pages at:
<http://www.nordicestforum.org>



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